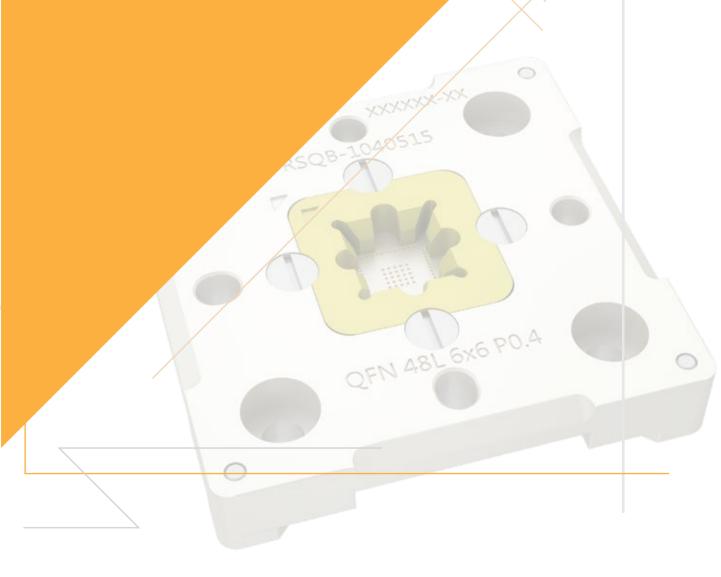
Semiconductor Testing Solutions

Testing Solutions
IC Testing Probes







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C.C.P Contact Probes Co., Ltd. was founded in 1986 with the goal "to set new quality standards in the industry and put customer satisfaction at the core of the business."

C.C.P. has started as a specialized provider of test probes and socket auxiliary solutions and has slowly expanded its product portfolio in related industries such as electronic component manufacturing. Our customized manufacturing equipment and strong research team enable us to stay at the forefront of the industry and develop products that reach the highest standards in terms of quality and availability.

After years of continuous growth, C.C.P. went public in 2001 and got listed on the Taiwan Stock Exchange in 2003. As of today, C.C.P. has subsidiaries in the U.S.A., China, Germany, India, Singapore, Japan and Korea, meeting demands from customers around the globe.

Apart from superior product quality, C.C.P. is committed to delivering excellent customer support, fast responses, and engaging customer interaction.



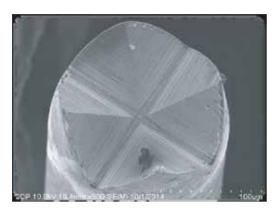
B.C.E. s.r.l.



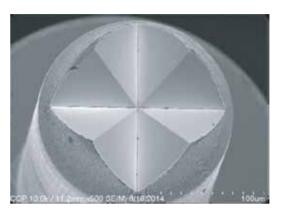


C.C.P. Strengths

Mirror process







Mirror process

C.C.P. consistently delivers high-quality products by optimizing the production process. The results are extremely durable and reliable products that meet our client's expectations.

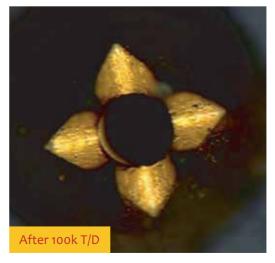
One of these cutting-edge technologies is called "Mirror Process" which significantly improves the surface quality of the pin tip.

- Less chance for solder migrating
- Less probe cleaning neccessary

Tip appearance comparison after 100,000 touchdowns



Normal



Mirror process **B.C.E. s.r.l.**

Via Regina Pacis, 54/c - 41049 SASSUOLO (MO) Italy
Tel. +39 0536 811.616 r.a. - Fax +39 0536 811.500

www.bce.it - E-mail: bce@bce.it





C.C.P. Strengths

Plating Line



C.C.P. is specialized in thick-layer Au-plating (over 1500 "), blind-hole plating (Aspect Ratio >6.5:1), precious metals processing (Pd alloy), etc.

C.C.P. has its own plating facility and technology. All materials we receive go through a strict quality control and materials used are certified by RoHS. Our plating technology is the result of more than 20 years of in-house research and delivers an industry leading performance for our products.



Advanced Analysis Equipment



Optical ProfilerSurface roughness inspection and measurement.



Nanoindenter
Plating hardness measurement.

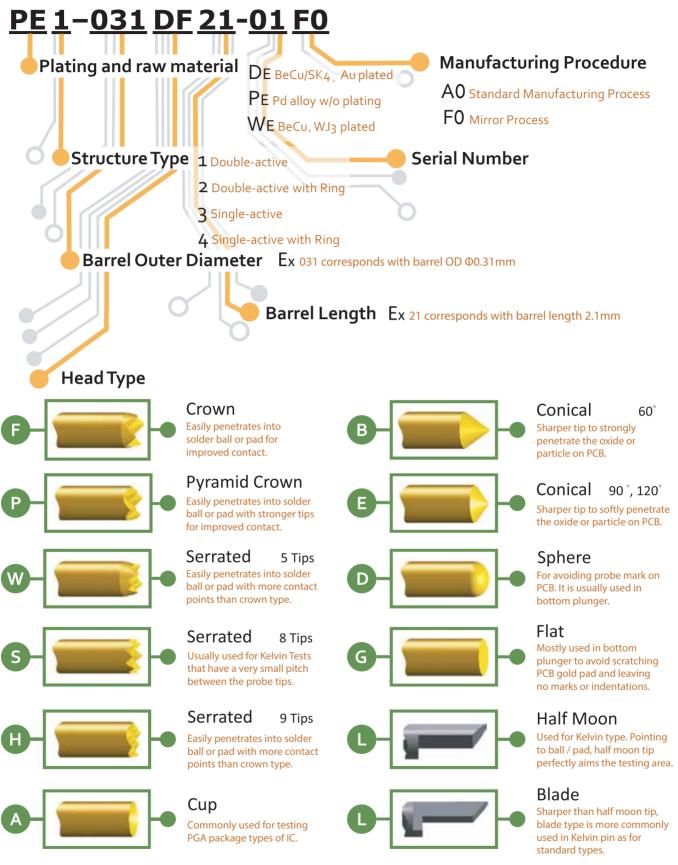


Surface observation with EDS for material analysis.



















General Final Test

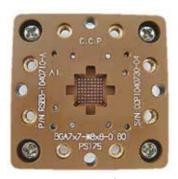
C.C.P. has over 25 years of experience in the development and manufacturing of sockets and pins. Our research and development teams are constantly improving the materials and manufacturing process to offer our customers the best solutions. We have developed more than 300 customized pins and over 50 special pins that are designed to withstand high currents, high-temperature environments or can handle high frequency data transmission.

Design Concept

Applied IC package BGA, QFN, QFP, LGA, CSP

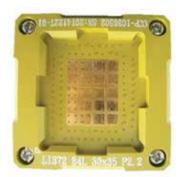


QFN Socket Pitch o.3mm



BGA Socket Pitch o.8mm

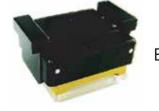
Pitch 0.2~2.2mm



LGA Socket Pitch:2.2mm

General IC Test Socket	Specification
IC Package Size	1.5X1.5~38X38 mm²
Min. Pitch	o.2mm
Material	Torlon 4203, Torlon 5530, PEEK, PEEK ceramic, SCP 5000
Data Rate	6 Gpbs/8 Gpbs/12 Gpbs Performance will be different according to testing condition
Life Time (Pin)	>200K



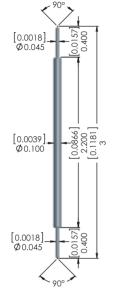


Block



Unit:mm; []:in

PE1-010EE22-01A0



Material

Top Plunger
Pd alloy
Barrel
Ni alloy
Spring
SWP , Au plated
Bottom Plunger
Pd alloy

Mechanical Spec.

Recommened Travel

0.35mm

Full Travel

o.50mm

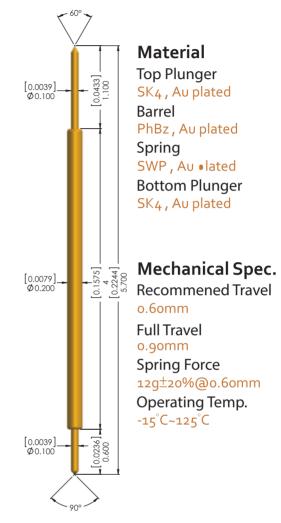
Spring Force

7g±20%@0.35mm

Operating Temp.

-15°C~125°C

DE1-020BE40-01A0



Electrical Spec. Pitch: 0.2mm Socket Material: Peek 1000



Current Rating 0.6A continuous Contact Resistance $<300m\Omega(AVG)$ Characteristic Impedance 80.8Ω Insertion Loss -1dB@9.9GHz Return Loss -20dB@2.48GHz Time Delay 13.74 psec

Loop Inductance 1.11 nH
Capacitance 0.17 pF

Electrical Spec.



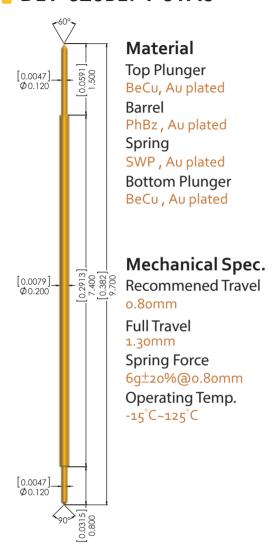
Current Rating 1A continuous Contact Resistance $<200 \text{m}\Omega(\text{AVG})$ Characteristic Impedance 55.9Ω Insertion Loss -1 dB > 20 GHz Return Loss -20 dB @ 12.88 GHz Time Delay 26.83 psec Loop Inductance 1.5 nH Capacitance 0.48 pF



Unit:mm; []:in

C.C.P. Contact Probes Co., Ltd.

DE1-020BE74-01A0

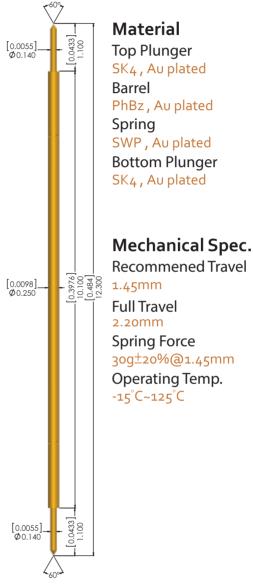


Electrical Spec.



Current Rating 0.5A continuous Contact Resistance $<200 \text{m}\Omega(AVG)$ Characteristic Impedance 53.07Ω Insertion Loss -1dB >20GHz Return Loss -20dB@8.14GHz Time Delay 46.17psec Loop Inductance 2.45 nH Capacitance 0.87 pF

DE1-025BB10-02A0



Electrical Spec.



Current Rating 1A continuous Contact Resistance <175m $\Omega(AVG)$ Characteristic Impedance 51.31Ω Insertion Loss -1dB>20GHz Return Loss -2odB@7.63GHz Time Delay 55.93 psec Loop Inductance 2.87 nH Capacitance 1.09 pF





Unit:mm; []:in

PE4-025EF24-01A0

[0.0047] 0.120 0.0094 [0.0079] 0.200 [0.0098] Ø0.250 [0.0126] Ø0.320 [0.0098] $\phi_{0.250}$ 0.0043

Material

Top Plunger Pd alloy Barrel PhBz, Au plated Spring SWP, Au plated Bottom Plunger BeCu, Au plated

Mechanical Spec.

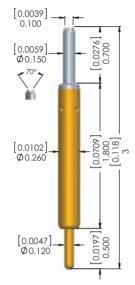
Recommened Travel

o.4omm

Full Travel 0.51mm **Spring Force** 23g±20%@0.40mm Operating Temp.

-15°C~125°C

PE3-026DF17-01F0



Material

Top Plunger Pd alloy Barrel PhBz, Au plated Spring SWP, Au plated **Bottom Plunger** BeCu, Au plated

Mechanical Spec.

Recommened Travel

0.35mm

Full Travel o.50mm Spring Force 20g±20%@0.35mm

Operating Temp. -15°C~125°C

Electrical Spec. Pitch: 0.4mm Socket Material: Peek 1000



Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 50.15Ω Insertion Loss -1dB>20GHz Return Loss -2odB>2oGHz

Time Delay 16.55 psec Loop Inductance o.83 nH Capacitance 0.33 pF

Electrical Spec.



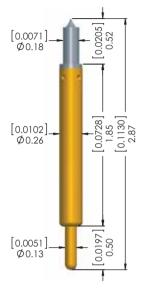
Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 57.68Ω Insertion Loss -1dB>20GHz Return Loss -20dB@9.16GHz Time Delay 13.31 psec Loop Inductance 0.77 nH Capacitance 0.23 pF



Unit:mm; []:in

C.C.P. Contact Probes Co., Ltd.

PE3-026BD18-01A0



Material

Top Plunger Pd alloy Barrel PhBz, Au plated Spring SWP, Au • lated **Bottom Plunger** BeCu, Au plated

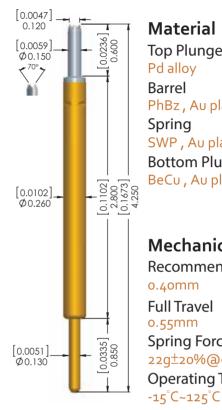
Mechanical S • ec.

Recommened Travel

o.30mm

Full Travel o.40mm **Spring Force** 24g±20%@0.30mm Operating Temp. -15°C~125°C

PE3-026DF27-01F0



Material

Top Plunger Pd alloy Barrel PhBz, Au plated Spring SWP, Au plated **Bottom Plunger** BeCu, Au plated

Mechanical Spec.

Recommened Travel o.4omm **Full Travel** 0.55mm **Spring Force** 22g±20%@0.40mm Operating Temp.

Electrical Spec.



Current Rating 1A continuous Contact Resistance <75m $\Omega(AVG)$ Characteristic Impedance 54.77 Ω Insertion Loss -1dB@>20GHz Return Loss -2odB@16GHz Time Delay 12.6 psec Loop Inductance o.69 nH Capacitance 0.23 pF

Electrical Spec.



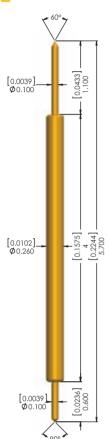
Current Rating 1A continuous Contact Resistance <75m $\Omega(AVG)$ Characteristic Impedance 54Ω Insertion Loss -1dB>20GHz Return Loss -20dB@18.9GHz Time Delay 21.7 psec Loop Inductance 1.18 nH Capacitance 0.40 pF





Unit:mm; []:in

DE1-026BE40-01A0



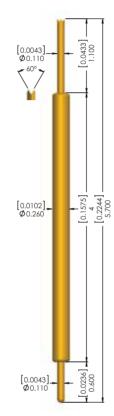
Material

Top Plunger BeCu, Au plated Barrel PhBz, Au plated Spring SUS, Au plated **Bottom Plunger** BeCu, Au plated

Mechanical Spec.

Recommened Travel 0.65mm **Full Travel** 1.00mm **Spring Force** 14g±20%@0.65mm Operating Temp. -55°C~150°C

DE1-026DF40-02A0



Material

Top Plunger BeCu, Au plated Barrel PhBz, Au plated Spring SUS, Au plated **Bottom Plunger** BeCu, Au plated

Mechanical Spec.

Recommened Travel 0.65mm **Full Travel** 0.85mm **Spring Force** 18g±20%@0.65mm Operating Temp.

-55°C~150°C

Electrical Spec. Pitch: 0.4mm Socket Material: Peek 1000



Current Rating 1A continuous Contact Resistance <175m $\Omega(AVG)$ Characteristic Impedance 49.46Ω Insertion Loss -1dB@16.7 GHz Return Loss -20dB@8.23GHz Time Delay 27.7 psec Loop Inductance 1.37 nH Capacitance 0.56 pF

Electrical Spec.



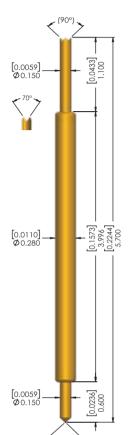
Current Rating 1A continuous Contact Resistance <175m $\Omega(AVG)$ Characteristic Impedance 47.71 Ω Insertion Loss -1dB@17.81GHz Return Loss -2odB@6.45GHz Time Delay 27.67 psec Loop Inductance 1.32 nH Capacitance 0.58 pF



Unit:mm; []:in

C.C.P. Contact Probes Co., Ltd.

DE1-028EF40-05A0



Material

Top Plunger
SK4, Au plated
Barrel
PhBz, Au plated
Spring
SWP, Au plated
Bottom Plunger
SK4, Au plated

Mechanical Spec.

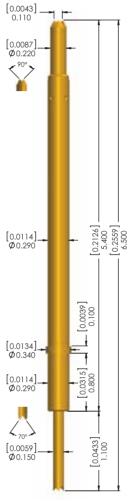
Recommened Travel o.65mm

Full Travel

Spring Force 28g±20%@0.65mm

Operating Temp. $-15^{\circ}\text{C} \sim 125^{\circ}\text{C}$

DE4-029FF45-01A0



Material

Top Plunger
SK4, Au plated
Barrel
PhBz, Au plated
Spring
SWP, Au plated
Bottom Plunger
BeCu, Au plated

Mechanical Spec.

Recommened Travel 0.70mm

0./0111111

Full Travel
1.10mm
Spring Force

30g±20%@0.70mm Operating Temp.

-15°C~125°C

Electrical Spec. Pitch: 0.4mm Socket Material: Peek



Current Rating 1A continuous Contact Resistance $<175m\Omega(AVG)$ Characteristic Impedance 49.6Ω Insertion Loss -1dB@17.49GHz Return Loss -2odB@7.92GHz Time Delay 27.7 psec Loop Inductance 1.38nH Capacitance 0.56 pF

Electrical Spec.



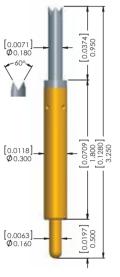
Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 44.38Ω Insertion Loss -1dB>20GHz Return Loss -2odB@3.77GHz Time Delay 28.84 psec Loop Inductance 1.28 nH Capacitance 0.65 pF





Unit:mm; []:in

PE3-030DF17-03A0



Material

Top Plunger Pd alloy

Barrel PhBz, Au plated Spring SWP, Au plated

Bottom Plunger BeCu, Au plated

Mechanical Spec.

Recommened Travel

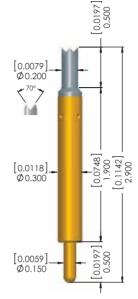
0.35mm

Full Travel 0.45mm

Spring Force 27g±20%@0.35mm

Operating Temp. -15°C~125°C

PE3-030DF18-01A0



Material

Top Plunger Pd alloy Barrel PhBz, Au plated Spring SWP, Au plated

Bottom Plunger BeCu, Au plated

Mechanical Spec.

Recommened Travel

o.40mm

Full Travel o.50mm **Spring Force** 35g±20%@0.40mm

Operating Temp. -15°C~125°C

Electrical Spec.

Capacitance 0.31 pF



Pitch: 0.4mm Socket Material: Peek 1000 Current Rating 1A continuous Contact Resistance <75m $\Omega(AVG)$ Characteristic Impedance 48.19Ω Insertion Loss -1dB>20GHz Return Loss -20dB@8.59GHz Time Delay 14.94 psec Loop Inductance 0.72 nH

Electrical Spec.



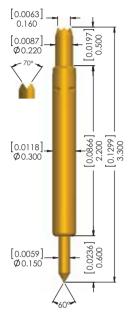
Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 42.36Ω Insertion Loss -1dB>20GHz Return Loss -2odB@6.47GHz Time Delay 14.4 psec Loop Inductance 0.61 nH Capacitance 0.34 pF



Unit:mm; []:in

C.C.P. Contact Probes Co., Ltd.

DE3-030BF21-03F0



Material

Top Plunger
BeCu , Au plated
Barrel
PhBz, Au plated
Spring
SWP , Au plated
Bottom Plunger
BeCu , Au plated

Mechanical Spec.

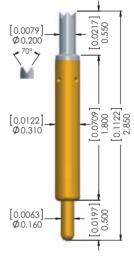
Recommened Travel

o.4omm

Full Travel
o.55mm
Spring Force
30g±20%@o.40mm
Operating Temp.

-15°C~125°C

PE3-031DF17-03F0



Material

Top Plunger
Pd alloy
Barrel
PhBz , Au plated
Spring
SWP , Au plated
Bottom Plunger
BeCu , Au plated

Mechanical Spec.

Recommened Travel

0.35mm

Full Travel
o.45mm
Spring Force
35g±20%@o.35mm
Operating Temp.
-15°C~125°C

Electrical Spec.



Pitch: 0.4mm Socket Material: Peek 1000 Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 42Ω Insertion Loss -1dB>20GHz Return Loss -20dB@7.15GHz Time Delay 16.4psec Loop Inductance 0.69nH Capacitance 0.39pF

Electrical Spec.



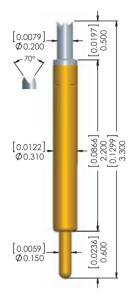
Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance $39.9\,\Omega$ Insertion Loss -1dB>20GHz Return Loss -20dB@4.5GHz Time Delay 14.7 psec Loop Inductance 0.59 nH Capacitance 0.37 pF





Unit:mm; []:in

PE3-031DF21-03F0



Material

Top Plunger
Pd alloy
Barrel
PhBz , Au plated
Spring
SWP , Au plated
Bottom Plunger
BeCu , Au plated

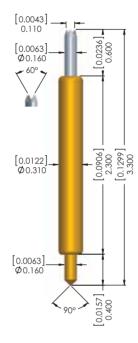
Mechanical Spec.

Recommened Travel

0.35 mm

Full Travel 0.60mmSpring Force $35g\pm20\%@0.35mm$ Operating Temp. $-15^{\circ}C\sim125^{\circ}C$

PE1-031EF23-02F0



Material

Top Plunger
Pd alloy
Barrel
PhBz , Au plated
Spring
SWP , Au plated
Bottom Plunger
BeCu , Au plated

Mechanical S • ec. Recommened Travel

o.4omm
Full Travel
o.65mm
Spring Force
30g±20%@o.4omm
Operating Temp.
-15°C~125°C

Electrical Spec. Pitch: 0.4mm Socket Material: Peek 1000



Current Rating $_1A$ continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance $_42.67\Omega$ Insertion Loss $_1dB>_20GHz$ Return Loss $_20dB@_5.08GHz$ Time Delay $_16.64psec$ Loop Inductance $_0.71nH$ Capacitance $_0.39pF$

Electrical Spec.



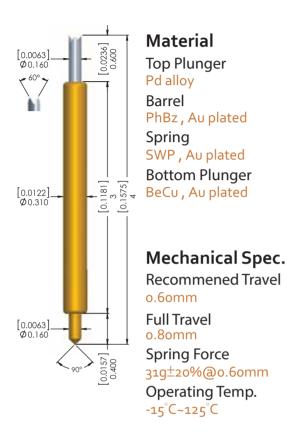
Current Rating 1A continuous Contact Resistance <175m Ω (AVG) Characteristic Impedance 40.14 Ω Insertion Loss -1dB>20GHz Return Loss -2odB@4.15GHz Time Delay 14.45 psec Loop Inductance 0.58 nH Capacitance 0.36 pF



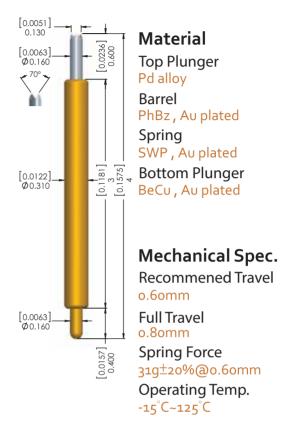
Unit:mm; []:in

C.C.P. Contact Probes Co., Ltd.

PE1-031EF30-02F0



PE1-031DF30-01F0



Electrical Spec. Pitch: 0.4mm Socket Material: Peek 1000



Current Rating 1A continuous Contact Resistance $<175m\Omega(AVG)$ Characteristic Impedance 39.53Ω Insertion Loss -1dB>20GHz Return Loss -2odB@3.63GHz Time Delay 18.97 psec Loop Inductance 0.75 nH Capacitance o.48 pF

Electrical Spec.



Current Rating 1A continuous Contact Resistance $<175m\Omega(AVG)$ Characteristic Impedance 40Ω Insertion Loss -1dB>20GHz Return Loss -2odB@3.9GHz Time Delay 19.7 psec Loop Inductance o.8 nH Capacitance 0.49 pF



Unit:mm; []:in

DE1-031DG40-01A0

[0.0059] \$\phi_{0.150}\$ | \$\phi_{0.150}

Material

Top Plunger
BeCu, Au plated
Barrel
PhBz, Au plated
Spring
SWP, Au plated
Bottom Plunger
BeCu, Au plated

Mechanical Spec.

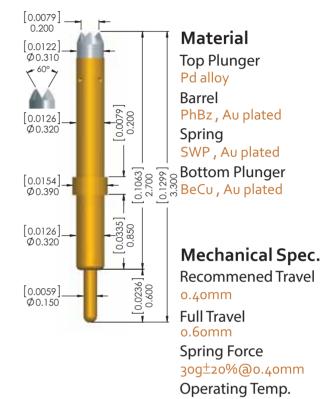
Recommened Travel o.65mm

Full Travel

Spring Force 37g±20%@0.65mm Operating Temp.

-15°C~125°C

PE4-032DF24-03F0



Electrical Spec.



Pitch: 0.4mm Socket Material: Peek 1000 Current Rating 1A continuous Contact Resistance <175m Ω (AVG) Characteristic Impedance 42.8 Ω Insertion Loss -1dB@17.68GHz Return Loss -2odB@4.05GHz Time Delay 27.97 psec Loop Inductance 1.2 nH Capacitance 0.65 pF

Electrical Spec.



-15°C~125°C

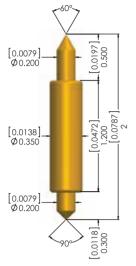
Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance $43.3\,\Omega$ Insertion Loss -1dB>20GHz Return Loss -2odB@5.44GHz Time Delay 18.2 psec Loop Inductance 0.79 nH Capacitance 0.42 pF



Unit:mm; []:in

C.C.P. Contact Probes Co., Ltd.

DE1-035BE12-01A0



Material

Top Plunger BeCu, Au plated Barrel PhBz, Au plated Spring SWP, Au plated **Bottom Plunger** BeCu, Au plated

Mechanical Spec.

Recommened Travel

o.30mm

Full Travel o.40mm

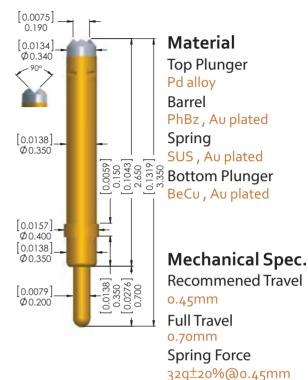
Spring Force

18g±20%@0.30mm

Operating Temp.

-15°C~125°C

PE4-035DF24-01F0



Electrical Spec. Pitch: 0.5mm Socket Material: Peek 1000



Current Rating 1A continuous Contact Resistance $<175m\Omega(AVG)$ Characteristic Impedance 34.74Ω Insertion Loss -1dB>20GHz Return Loss -2odB@4.08GHz Time Delay 10.07 psec Loop Inductance 0.35nH Capacitance 0.29pF

Electrical Spec.



Operating Temp.

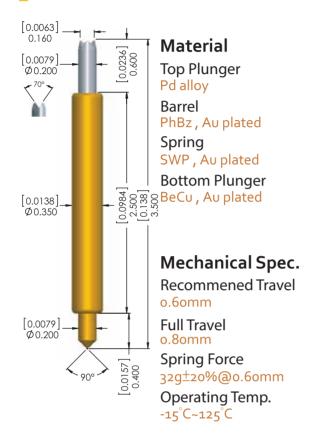
-55°C~150°C

Current Rating 1A continuous Contact Resistance <75m $\Omega(AVG)$ Characteristic Impedance 39.8 Ω Insertion Loss -1dB>20GHz Return Loss -20dB@3.94GHz Time Delay 17.5 psec Loop Inductance 0.70 nH Capacitance 0.44 pF

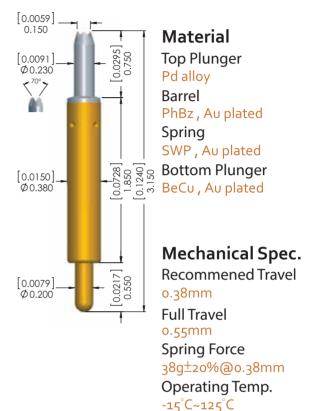


Unit:mm; []:in

PE1-035EF25-01F0



PE3-038DF17-03F0



Electrical Spec. Pitch: 0.5mm Socket Material: Peek 1000



Current Rating 1A continuous Contact Resistance <175m $\Omega(AVG)$ Characteristic Impedance 44Ω Insertion Loss -1dB>20GHz Return Loss -2odB@ 8.48GHz Time Delay 18.5psec Loop Inductance o.82nH Capacitance 0.42pF

Electrical Spec.



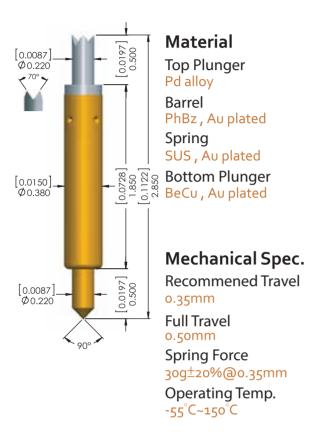
Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 45.08 Ω Insertion Loss -1dB>20GHz Return Loss -20dB@5.69GHz Time Delay 13.97 psec Loop Inductance o.63 nH Capacitance 0.31 pF



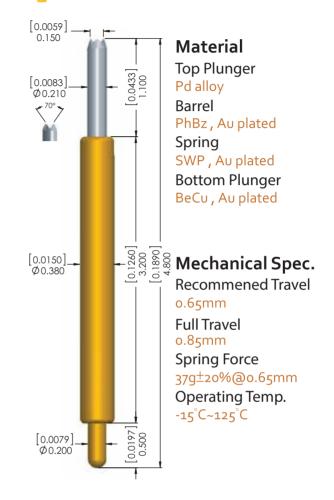
Unit:mm; []:in

C.C.P. Contact Probes Co., Ltd.

PE3-038EF17-04A0



PE1-038DF32-02F0



Electrical Spec.



Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 39.8 Ω Insertion Loss -1dB>20GHz Return Loss -2odB@4.5GHz Time Delay 15.5 psec Loop Inductance o.62 nH Capacitance 0.39 pF

Electrical Spec.



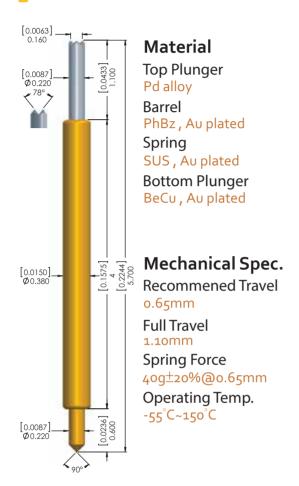
Current Rating 1A continuous Contact Resistance $<175m\Omega(AVG)$ Characteristic Impedance 39.5Ω Insertion Loss -1dB>20GHz Return Loss -20dB@3GHz Time Delay 25.2 psec Loop Inductance 1 nH Capacitance o.64 pF



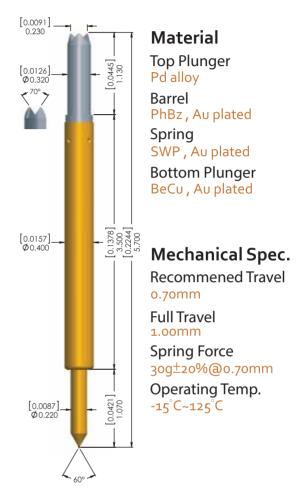


Unit:mm; []:in

PE1-038EP40-01A0



PE3-040BF34-01A0



Electrical Spec.



Current Rating 1A continuous Contact Resistance $<175m\Omega(AVG)$ Characteristic Impedance 42 \Omega Insertion Loss -1dB>20GHz Return Loss -2odB@3.82GHz Time Delay 29.9 psec Loop Inductance 1.26 nH Capacitance 0.71pF

Electrical Spec.



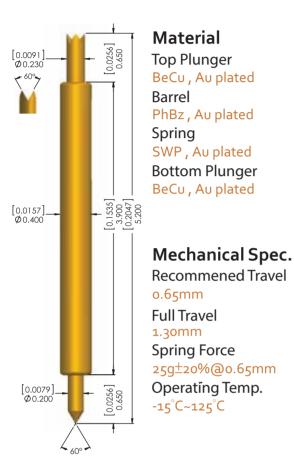
Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 38.29Ω Insertion Loss 1dB>20GHz Return Loss -20dB@2.16GHz Time Delay 27.95 psec Loop Inductance 1.07 nH Capacitance o.73 pF



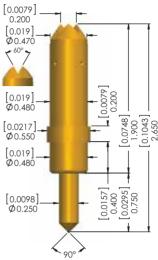
Unit:mm; []:in

C.C.P. Contact Probes Co., Ltd.

DE1-040BF39-030



DE4-048EF17-01F0



Material

Top Plunger BeCu, Au plated Barrel Brass, Au plated Spring SWP , Au plated **Bottom Plunger** BeCu, Au plated

Mechanical Spec.

Recommened Travel

o.50mm

Full Travel o.6omm Spring Force 27.5q±20%@0.50mm Operating Temp. -15°C~125°C



Current Rating 1A continuous Contact Resistance $<175m\Omega(AVG)$ Characteristic Impedance 36.58Ω Insertion Loss -1dB@15.1GHz Return Loss -20dB@1.99GHz Time Delay 25.97 psec Loop Inductance o.95nH Capacitance 0.71pF

Electrical Spec.



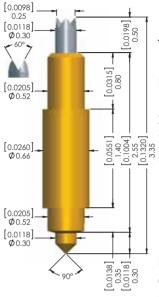
Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 36.5Ω Insertion Loss -1dB>20 GHz Return Loss -2odB@3.54GHz Time Delay 14.2 psec Loop Inductance o.52nH Capacitance 0.39 pF





Unit:mm; []:in

PE2-050EF25-01F0



Material

Top Plunger
Pd alloy
Barrel
PhBz , Au plated
Spring
SUS , Au plated
Bottom Plunger
BeCu , Au plated

Mechanical Spec.

Recommened Travel

0.45mm

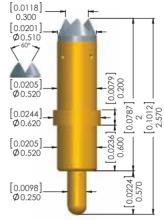
Full Travel

Spring Force

30g±20%@0.45mm Operating Temp.

-55°C~150°C

PE4-052DF17-01A0



Material

Top Plunger
Pd alloy
Barrel
PhBz, Au plated
Spring
SWP, Au plated
Bottom Plunger
BeCu, Au plated

Mechanical Spec.

Recommened Travel

o.40mm

Full Travel o.6omm

Spring Force 35g±20%@o.4omm

Operating Temp.

-15°C~125°C

Electrical Spec. Pitch: 0.8mm Socket Material: Peek 1000



Current Rating 1A continuous

Contact Resistance <175m $\Omega(AVG)$

Characteristic Impedance 34.8Ω

Insertion Loss 1dB>20GHz
Return Loss -20dB@2.25GHz

Time Delay 19.8psec

Loop Inductance o.69nH

Capacitance 0.57pF

Electrical Spec.



Pitch: o.8mm Socket Material: Peek 1000

Current Rating 1A continuous

Contact Resistance <75m $\Omega(AVG)$

Characteristic Impedance 38.7Ω

Insertion Loss -1dB>20 GHz
Return Loss -2odB@4.45GHz

Time Delay 15.4 psec

Loop Inductance o.6nH

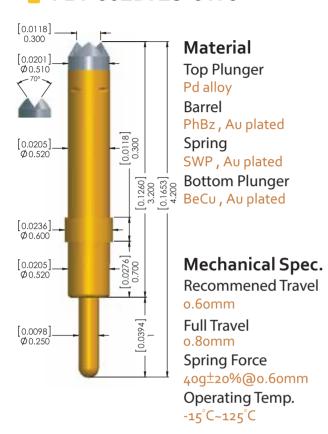
Capacitance o.4pF



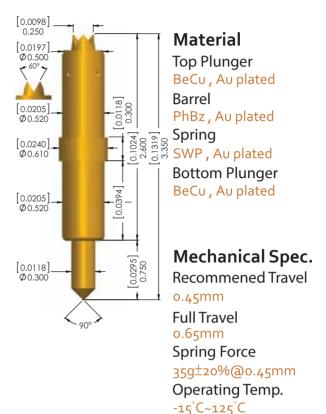
Unit:mm; []:in

C.C.P. Contact Probes Co., Ltd.

PE4-052DF28-01F0



DE4-052EF23-02F0



Electrical Spec. Pitch: o.8mm Socket Material: Peek 1000



Current Rating 1A continuous Contact Resistance <75m $\Omega(AVG)$ Characteristic Impedance 41.8Ω Insertion Loss -1dB@15.08GHz Return Loss -2odB@3.29GHz Time Delay 23.8 psec Loop Inductance 1nH

Electrical Spec.



Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 41.5Ω Insertion Loss -1dB>20GHz Return Loss -2odB@3.45GHz Time Delay 19.9 psec Loop Inductance o.83 nH Capacitance 0.48 pF

B.C.E. s.r.l.

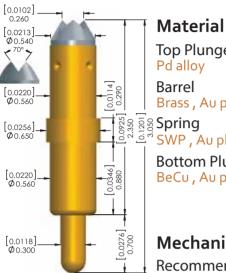
Capacitance 0.57pF





Unit:mm; []:in





Top Plunger Pd alloy Barrel Brass, Au plated

[52,605] [1021.0] [1021.0] [1021.0] [1021.0] [1021.0] [1021.0] [1021.0] [1021.0] [1021.0] [1021.0] [1021.0] [1021.0] [1021.0] SWP , Au plated

Bottom Plunger BeCu, Au plated

Mechanical Spec.

Recommened Travel

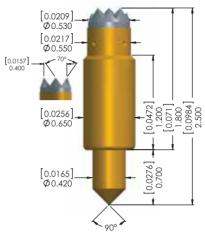
o.50mm

Full Travel o.70mm

Spring Force 35g±20%@0.50mm

Operating Temp. -15°C~125°C

PE4-065EW15-01A0



Material

Top Plunger Pd alloy Barrel PhBz, Au plated Spring SWP, Au plated **Bottom Plunger** BeCu, Au plated

Mechanical Spec.

Recommened Travel

o.50mm

Full Travel o.70mm

Spring Force

32g±20%@0.50mm

Operating Temp.

-15°C~125°C

Electrical Spec. Pitch: o.8mm Socket Material: Peek 1000



Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 32.68Ω Insertion Loss -1dB@17.48GHz Return Loss -20dB@1.93GHz Time Delay 19.28 psec Loop Inductance o.63nH Capacitance o.59pF

Electrical Spec. Pitch: o.8mm Socket Material: Peek 1000



Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 29Ω Insertion Loss -1dB@10.3GHz Return Loss -2odB@1.79GHz

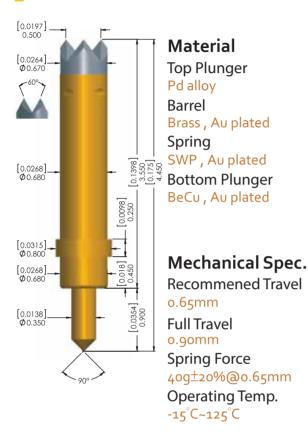
Time Delay 16 psec Loop Inductance 0.47 nH Capacitance 0.55 pF



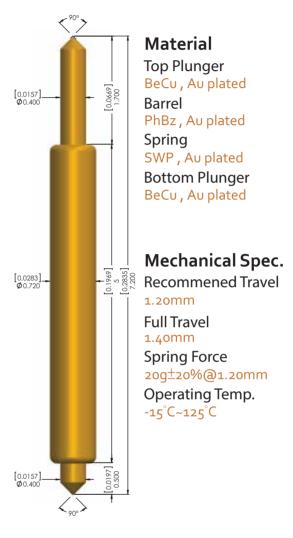
Unit:mm; []:in

C.C.P. Contact Probes Co., Ltd.

PE4-068EP35-01F0



DE1-072EE50-01A0



Electrical Spec. Pitch: 1.0mm Socket Material: Peek 1000



Current Rating 2A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 37.53 Ω Insertion Loss -1dB@11.91GHz Return Loss -20dB@2.19GHz Time Delay 26.65 psec Loop Inductance 1 nH Capacitance 0.71 pF

Electrical Spec.

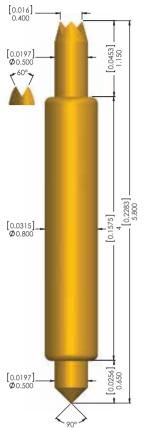


Current Rating 1A continuous Contact Resistance <175m $\Omega(AVG)$ Characteristic Impedance 40.7Ω Insertion Loss -1dB@13.9GHz Return Loss -20dB@2.37GHz Time Delay 38.7 psec Loop Inductance 1.58 nH Capacitance 0.95 pF



Unit:mm; []:in

DE1-080BF40-010



Material Top Plunger BeCu, Au plated Barrel PhBz, Au plated Spring SWP, Au plated

Bottom Plunger BeCu, Au plated

Mechanical Spec.

Recommened Travel

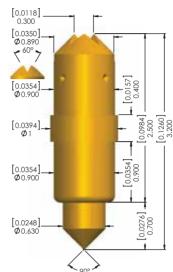
0.70mm

Full Travel 1.05mm

Spring Force 30g±20%@0.70mm

Operating Temp. -15°C~125°C

DE4-090EF25-02F0



Material

Top Plunger BeCu, Au plated Barrel Brass, Au plated Spring SUS, Au plated **Bottom Plunger** BeCu, Au plated

Mechanical Spec.

Recommened Travel

o.50mm

Full Travel o.70mm

Spring Force 30g±20%@0.50mm

Operating Temp.

-55°C~150°C

Electrical Spec. Pitch: 1.0mm Socket Material: Peek 1000



Current Rating 3A continuous Contact Resistance $<175m\Omega(AVG)$ Characteristic Impedance 33.9 Ω Insertion Loss -1dB@12GHz Return Loss -20dB@1.22GHz Time Delay 33.6 psec Loop Inductance 1.14nH Capacitance o.99pF

Electrical Spec. Pitch: 1.27mm Socket Material: Peek 1000



Current Rating 1A continuous Contact Resistance <75m $\Omega(AVG)$ Characteristic Impedance 34.6Ω Insertion Loss -1dB@17.27GHz Return Loss -20dB@2.16GHz Time Delay 20.4 psec Loop Inductance 0.71 nH

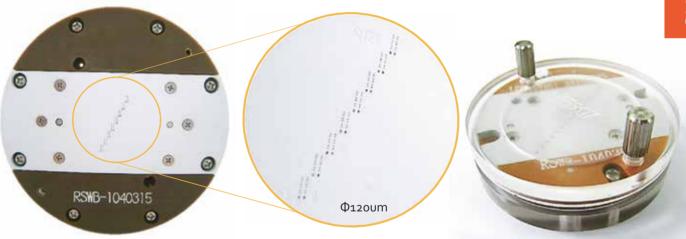
Capacitance 0.59 pF



Wafer-Level CSP Test

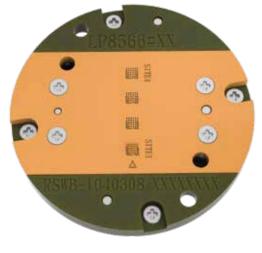
With the massive growth of WLCSP in the semiconductor market, C.C.P. has designed over 30 different kinds of probe heads to meet the demand of the market. A pogo pin design improves the durability of the probe head. Additionally, coplanarity errors induced by differently sized solder balls can be avoided by our pogo pins which have a working travel designed for 250um. We offer a wide variety of head types to meet our client's needs.

Design Concept



8 balls, pitch 0.5mm

C.CP employs a combination of industry-leading high precision machines from renowned manufacturers as well as custom made equipment. This allows us to drill holes smaller than Φ 60 μ m.



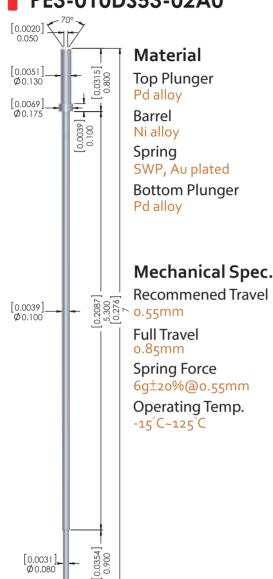
36 balls, pitch 0.4mm

Probe Head	Specification
Min. Pitch	0.1 ₅ mm
Max. Site Counts	32 sites
Top Housing Material	Photoveel® /VESPEL®SCP5000
Mounting Plate Material	Torlon® 5530
Bottom Housing Material	VESPEL®SCP5000
Life Time (Pin)	>300,000

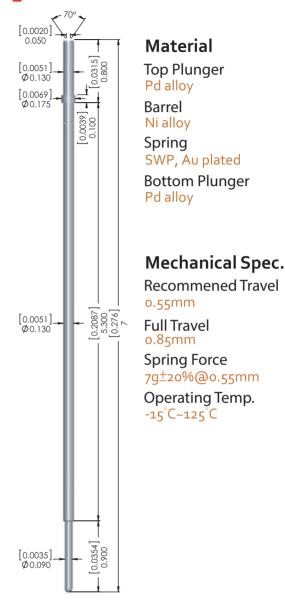


Unit:mm; []:in

PE3-010DS53-02A0



PE3-013DS53-01F0



Electrical Spec.

Current Rating 0.2A continuous Contact Resistance $<500m\Omega(AVG)$ Characteristic Impedance 91.77Ω Insertion Loss -1dB@3.76GHz Return Loss -2odB@o.72GHz Time Delay 34.87 psec Loop Inductance 3.2 nH Capacitance 0.38 pF

Electrical Spec.

Pitch: 0.3mm Socket Material: Peek 1000



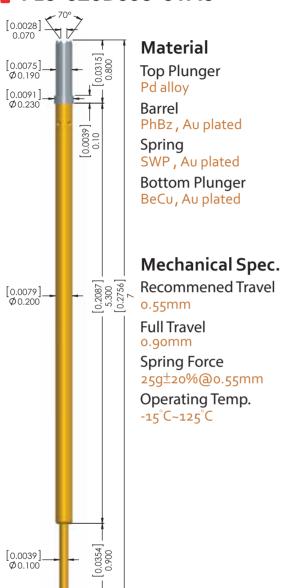
Current Rating 0.4 A continuous Contact Resistance $<500m\Omega(AVG)$ Characteristic Impedance 91.3Ω Insertion Loss -1dB@1.47GHz Return Loss -20dB@0.43GHz

Time Delay 42.9 psec Loop Inductance 3.92 nH Capacitance 0.47pF

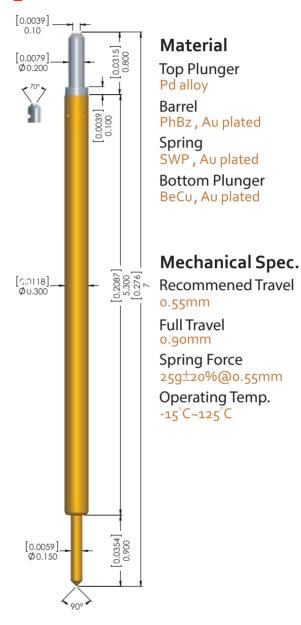


Unit:mm; []:in

PE3-020DS53-01A0



PE3-030EF53-01A0



Electrical Spec. Pitch: 0.4mm Socket Material: Peek



Current Rating 0.6A continuous Contact Resistance $<300 \text{m}\Omega(\text{AVG})$ Characteristic Impedance $66.62\,\Omega$ Insertion Loss -1dB>20GHz Return Loss -20dB@1.84GHz Time Delay 37.97 psec Loop Inductance 2.32 nH Capacitance 0.57 pF

Electrical Spec. Pitch: 0.4mm Socket Material: Peek 1000



Current Rating 1A continuous Contact Resistance $^{175m}\Omega(AVG)$ Characteristic Impedance $^{42\cdot3}\Omega$ Insertion Loss $^{-1dB}$ >20 GHz Return Loss $^{-2odB}$ @ 3 GHz Time Delay $^{34\cdot7}$ psec Loop Inductance $^{1.47}$ nH Capacitance $^{0.82}$ pF



High Current Solutions

C.C.P. offers a patented solution for high current pogo pin testers that can be used in a variety of applications such as EV Battery testing or other industrial applications. The design is customizable and can be fitted to your specific requirements. The design offers a much more reliable current flow and reduces the wear on the tester significantly.

Design Concept

Double-Ended High Current Probe for IC Testing



Current Path of...

Normal pin: Blue line High current pin: Red line

Taiwan Patent No. M453149

Generally, the current runs from the bottom plunger through the barrel wall to the top plunger. Due to that, the contact resistance between the wall and plunger will increase gradually. This can cause the spring to burn and lead to a failure at higher currents. The straight plunger in the center of the high current pin allows the current to take a direct route, to the top plunger and in consequences avoids flowing through the spring during testing.

Single High Current Pin for Lithium Battery Testing



CCP developed a special design which is different from standard testing pins to improve the current carrying capabilities of our high current pin.

Coaxial High Current Pin for Lithium Battery Testing



This coaxial high current pin combines a sensor pin with a current test pin in one probe design. The one-piece design of the current test pin improves the electrical resistance significantly.



Probe Specifications (IC Testing Probe)

Unit:mm; []:in

DE4-029DW25-01A0

[0.0106] Ø0.270 [0.0114] [0.0130] Ø0.330 [0.0063] Ø0.160 [0.0055] Ø0.140 [0.0047] Ø0.120

Material Top Plunger BeCu, Au plated

Barrel PhBz, Au plated Spring SUS, Au plated **Bottom Plunger**

BeCu, Au plated

Mechanical Spec.

Recommened Travel

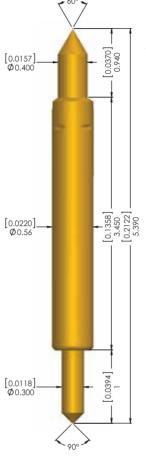
o.4omm

Full Travel o.70mm

Spring Force 25q±20%@0.40mm

Operating Temp. -55°C~150°C

DE3-056BE34-01A0



Material

Top Plunger BeCu, Au plated Barrel Brass, Au plated Spring SUS, Au plated **Bottom Plunger** BeCu, Au plated

Mechanical Spec.

Recommened Travel 0.67mm

Full Travel 0.95mm

Spring Force

35q±20%@0.67mm Operating Temp.

-55°C~150°C

Electrical Spec. Pitch: 0.5mm Socket Material: Peek 1000



Current Rating 3A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 52.7 Ω Insertion Loss -1dB>20GHz Return Loss -2odB@1oGHz

Time Delay 18.97 psec Loop Inductance 1.00 nH

Capacitance o.36 pF

Electrical Spec.



Current Rating 5A continuous Contact Resistance $<75m\Omega(AVG)$

Characteristic Impedance 32.1Ω

Insertion Loss -1dB@6.27GHz

Return Loss -20dB@1.2GHz Time Delay 29.5 psec

Loop Inductance o.95nH

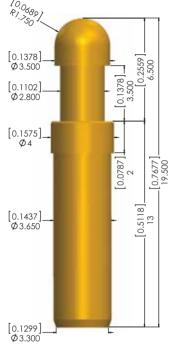
Capacitance 0.92pF



Probe Specifications (Battery Testing Probe)

Unit:mm; []:in

H101001M1



Material

Plunger BeCu , Au plated Barrel

Barrel Brass, Au plated Spring SUS, Au plated

Mechanical Spec.

Recommened Travel 2.30mm

Full Travel 3.5mm

Spring Force

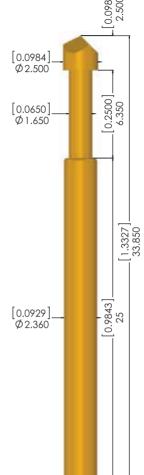
250g±20%@2.3mm Operating Temp.

-55°C~150°C

Current Rating

10 A

S-11T1-2545G



Material

Plunger

BeCu , Au plated

Barrel

Brass, Au plated Spring

SUS , Au plated

Mechanical Spec.

Recommened Travel 4.20mm

Full Travel 6.35mm

Spring Force 450g±20%@4.20mm

Operating Temp.

-55°C~150°C

Current Rating

6 A



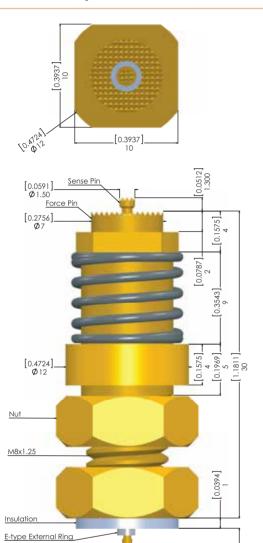
Application Demonstration

Probes touch the PCB to close the circuits and activate the lithium battery.



Probe Specifications (Battery Testing Probe)

Unit:mm; []:in



H050002M0

Material

<u>Sense Pin</u> Plunger

BeCu , Au plated

Barrel

PhBz , Au plated

Spring

SUS, Au plated

Force Pin

Plunger

BeCu, Au plated

Barrel

Brass, Au plated

Spring

SUS , Au plated

Nut

BeCu , Au plated Insulation

Teflon

Mechanical Spec.

Sense Pin

Recommened Travel

1.00mm

Full Travel

1.50mm

Spring Force

90g±20%@1.00mm

Force Pin

Recommened Travel

4.oomm

Full Travel

6.oomm

Spring Force

700g±20%@4.00mm

Current Rating

50 A



[0.0394] Ø1

Application Demonstration

We are able to customize our probes to meet your current carrying requirements. Several patented designs and proprietary, industry leading plating technologies will offer you the right solution for your application.

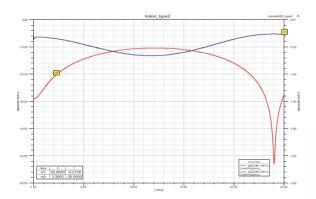
B.C.E. s.r.l.



High Frequency Solutions

High frequency testing is mostly used for radio-frequency channels and wide-band transaction applications. The signal pin can be customized according to the electrical characteristics and testing environments of the client. For IC testing, we usually recommend ultra-short pins, coaxial probes, and PCRs to accommodate the different types of ICs.

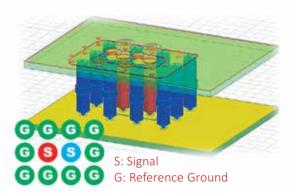
Design Concept



We have the ability to simulate 3D electromagnetic performance as well as S-parameters, inductance and impedance and by that improving SI characteristics.

Performance Simulation CCP utilizes HFSS to simulate the

CCP utilizes HFSS to simulate the pin performance in the sockets. This allows us to choose the best pin before designing a customized sockets.

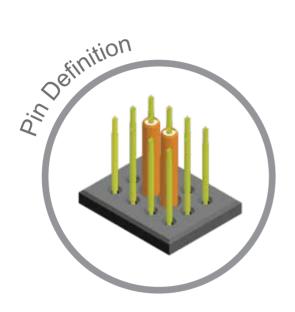




CCP has a dedicate high frequency lab that uses TDR, network analyzers and RF probe stations to measure the socket / pins actual performance and therby verifying the simulation results. These are all indispensable equipments for developing new high-class products.



Probe Specifications (Coaxial Probe)





Pin Definition







Application

Feature:

High Speed / High Frequency

DUT:

Bluetooth / GPS / LTE / Wireless IC / 5G

Packaging:

BGA / CSP / QFN / QFP

Specification

Insertion Loss:

-1dB @ >50 GHz

Return Loss:

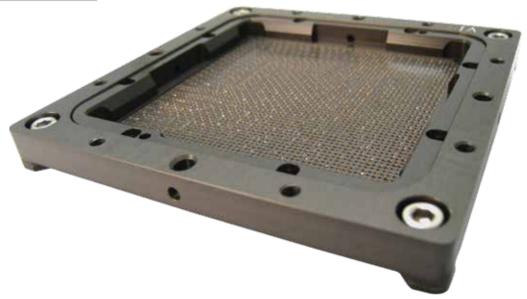
-20dB @ >30 GHz

Impedance:

50 Ohm

Pitch:

0.65~1.00 mm



B.C.E. s.r.l.

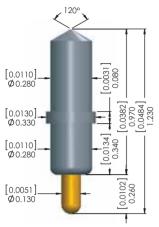




Probe Specifications (IC Test Probe)

Unit:mm; []:in





Material

Barrel Pd alloy Spring SUS, Au plated **Bottom Plunger** BeCu, Au plated

Mechanical Spec.

Recommened Travel

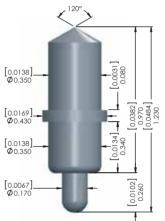
0.18mm

Full Travel 0.23mm

Spring Force 15g±20%@0.18mm

Operating Temp. -55°C~150°C

PE4-035DE09-01H0



Material

Barrel Pd alloy Spring SUS, Au plated **Bottom Plunger** Pd alloy

Mechanical Spec.

Recommened Travel

0.18mm

Full Travel 0.23mm **Spring Force** 14g±20%@0.18mm

Operating Temp.

-55°C~150°C

Electrical Spec.



Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 48.9 Ω Insertion Loss -1dB>20GHz Return Loss -20dB>20GHz Time Delay 7.3 psec Loop Inductance o.36 nH Capacitance 0.15 pF

Electrical Spec.



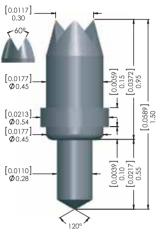
Current Rating 1A continuous Contact Resistance <75m $\Omega(AVG)$ Characteristic Impedance 37.4Ω Insertion Loss -1dB>20GHz Return Loss -2odB@7.62GHz Time Delay 7.48 psec Loop Inductance 0.28 nH Capacitance 0.2 pF



Probe Specifications (IC Test Probe)

Unit:mm; []:in

PE4-045EF09-01A0



Material

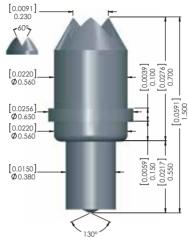
Barrel Pd alloy Spring SUS, Au plated Bottom plunger Pd allov

Mechanical Spec.

Recommended travel

o.4omm Full travel 0.55mm Spring force 30g±20%@0.40mm Operating Temp. -55°C~150°C

PE4-056EF09-01H0



Material

Barrel Pd alloy Spring SUS, Au plated Bottom plunger Pd alloy

Mechanical Spec.

Recommended travel o.4omm Full travel 0.55mm Spring force 31g±20%@0.40mm Operating Temp. -55°C~150°C

Electrical Spec.



Current Rating 1A continuous Contact Resistance <75m $\Omega(AVG)$ Characteristic Impedance 35.9 Ω Insertion Loss -1dB>20GHz Return Loss -2odB@5.54GHz Time Delay 8.6 psec

Loop Inductance 0.31 nH Capacitance 0.24 pF

Electrical Spec.





Current Rating 1A continuous Contact Resistance <75m $\Omega(AVG)$ Characteristic Impedance $^{29.7}\Omega$ Insertion Loss -1dB>20GHz Return Loss -20dB@ 2.9GHz Time Delay 10.4 psec

Loop Inductance 0.31nH Capacitance 0.35 pF



Kelvin Contact Solutions

The term Kelvin Contact is derived from the English physicist Lord Kelvin who invented the Kelvin Bridge in 1861. The Kelvin Bridge is used to measure unknown electrical resistors below 1Ω and is a modification of the Wheatstone bridge. The Kelvin contact solution by C.C.P. is using one of the pins to measure the current while the other is adjusting the applied voltage. As with all our products our engineers will adjust the product according to your specific needs.

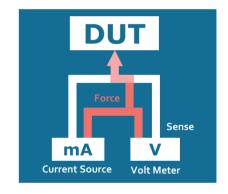
0.07~0.10mm

Design Concept

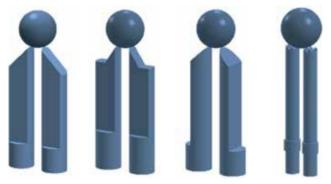
Kelvin Contact

Kelvin Contact is mostly used to test specific electrical signals, as well as be the route of current bypass when testing. C.C.P. innovated several types of kelvin pins to meet market demands.

Available in 70um~100um kelvin gap, allows precise contacts to balls / pads.



Different type of tip for various application



Blade Tip Ladder Tip Half Moon Tip Crown Tip

Kelvin Socket	Specification
IC Type	QFN,QFP,BGA
IC Size	2X2~20X20 mm²
Min. Pitch	o.3omm
Life Time (Pin)	>200,000

Blade: Common tip type for kelvin testing Ladder: Similar with blade type but more accurate positioning Half Moon: Mostly applied in QFN, QFP

Crown: No need to take the direction into account when manufacturing the socket and inserting the pins as each claw can prick the testing area.





Unit:mm; []:in

PE3-015DL38-01A0

[0.0035] Pd alloy [0.1535] 3.900 [0.2165] 5.500 [0.0059] Ø0.150 [0.0043] Ø0.110

Material

Top Plunger Pd alloy Barrel Ni allov Spring SUS **Bottom Plunger**

Mechanical Spec.

Recommened Travel

o.40mm

Full Travel o.70mm

Spring Force

20q±20%@0.40mm

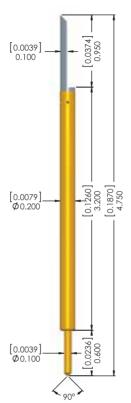
Operating Temp.

-55°C~150°C

Electrical Spec.

Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$

PE3-020EL31-01A0



Material

Top Plunger Pd alloy

PhBz, Au plated

Spring

SWP, Au plated

Bottom Plunger BeCu, Au plated

Mechanical Spec.

Recommened Travel

o.30mm

Full Travel

o.50mm

Spring Force

10g±20%@0.30mm

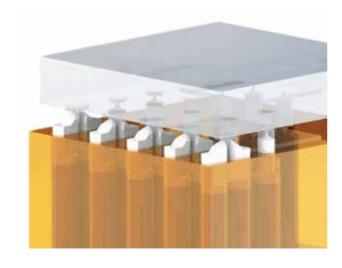
Operating Temp.

-15°C~125°C

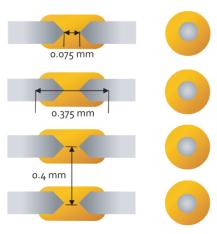
Electrical Spec.

Current Rating 2A continuous Contact Resistance $<75m\Omega(AVG)$

Half Moon Kelvin Socket Example



Pin Array



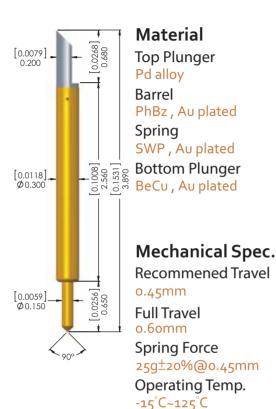




Unit:mm; []:in

PE3-030EL25-01A0

PE3-031EL38-01A0



[0.0122] Ø0.310

Material Top Plunger

Pd alloy

Barrel PhBz , Au plated Spring

SUS, Au plated Bottom Plunger

BeCu , Au plated

Mechanical Spec.

Recommened Travel o.6omm

Full Travel

0.75mm

Spring Force

32g±20%@0.60mm

Operating Temp. -55°C~150°C

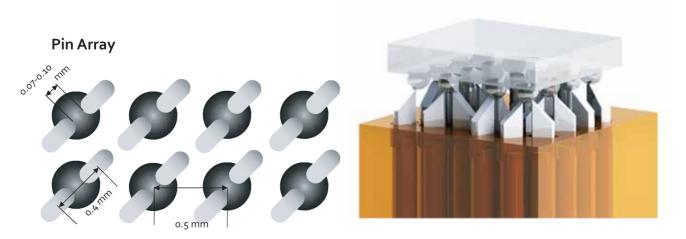
Electrical Spec.

Current Rating 3A continuous Contact Resistance $<75m\Omega(AVG)$

Electrical Spec.

Current Rating 3A continuous Contact Resistance $<75m\Omega(AVG)$

Blade Kelvin Socket Example





Memory Test Solutions

Memory ICs are a core component of nearly every electronic device. Memory ICs are usually categorized in volatile and non-volatile memory where volatile memory keeps its stored information when the power cycle is interrupted and volatile memory needs a constant power supply to retain its data. Most memory modules have a standardized format that can be tested with standardized test-pins. C.C.P. offers testing solutions for all common formats (DDR, Flash, eMCP, etc.) as well as customized testing solutions for your individual needs.

Design Concepts



Housing	Material	Housing	Spec.
Injection molding	PES	Min. Pitch	o.4mm



Manual DDR2/3	Testing	Module
Single	Side	



Manual DDR3 Testing Module Double Side

Manual DDR2/3 Testin	g Module
----------------------	----------

Max. Site Amount

Transmission Rate (MT/s)

Spec.

8~16 (Single side/ Double side)

200MHz~1866MHz

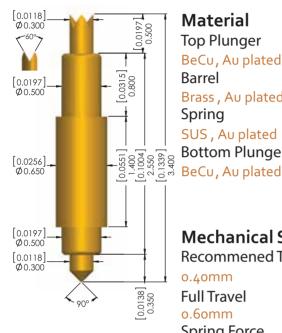




Unit:mm; []:in

DE2-050EF25-120





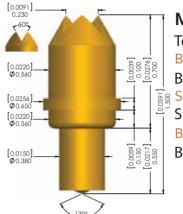
Material Top Plunger BeCu, Au plated Barrel Brass, Au plated Spring SUS, Au plated **Bottom Plunger**

Mechanical Spec. **Recommened Travel** o.4omm **Full Travel** o.6omm

Spring Force 35q±20%@0.40mm Operating Temp. -55°C~150°C

DE4-056EF09-03F0





Material Top Plunger BeCu, Au plated Barrel SUS, Au plated Spring BeCu, Au plated **Bottom Plunger**

Mechanical Spec.

Recommened Travel

o.4omm

Full Travel o.50mm

Spring Force

30g±20%@0.40mm

Operating Temp.

-55°C~150°C

Electrical Spec. Pitch: o.8mm Socket Material:



Current Rating 1A continuous Contact Resistance <175m $\Omega(AVG)$ Characteristic Impedance 37Ω Insertion Loss -1dB@18.6GHz Return Loss -2odB@2.69GHz Time Delay 20.4 psec Loop Inductance 0.76 nH Capacitance 0.55 pF

Electrical Spec.



Current Rating 1A continuous Contact Resistance <75m $\Omega(AVG)$ Characteristic Impedance 36.16Ω Insertion Loss -1dB>20GHz Return Loss -20dB@5.11GHz Time Delay 9.4 psec Loop Inductance o.34nH

Capacitance o.26pF



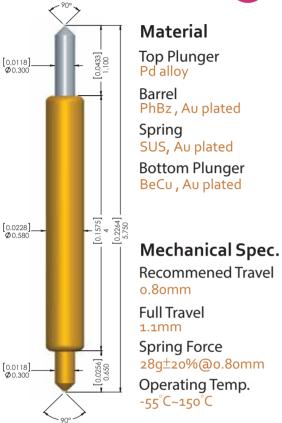
C.C.P. Contact Probes Co., Ltd.

Probe Specifications

Unit:mm; []:in

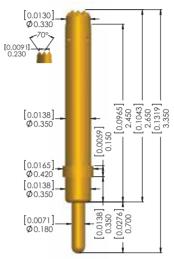
PE1-058EE40-01A0





DE4-035DH24-01A0





Material
Top Plunger
BeCu, Au plated
Barrel
PhBz, Au plated
Spring
SWP, Au plated
Bottom Plunger
BeCu, Au plated

Mechanical Spec.

Recommened Travel

o.5omm

Full Travel
o.7omm

Spring Force
27g±20%@o.5omm

Operating Temp.
-15°C~125°C

Electrical Spec. Pitch: 0.8mm Socket Material: Peek 1000



Current Rating 1 A continuous Contact Resistance 75 m $^{\Omega}$ (AVG) Characteristic Impedance $^{41.2}$ $^{\Omega}$ Insertion Loss $^{-1}$ dB> 20 GHz Return Loss $^{-2}$ odB@ $^{2.5}$ 6GHz Time Delay $^{32.2}$ psec Loop Inductance $^{1.33}$ nH Capacitance $^{0.78}$ pF

Electrical Spec.



Current Rating 1A continuous Contact Resistance $<75\text{m}\Omega(\text{AVG})$ Characteristic Impedance 40.06Ω Insertion Loss -1dB>20GHz Return Loss -2odB@4.5GHz Time Delay 17.22 psec Loop Inductance 0.69 nH Capacitance 0.43 pF





Burn In Test

The Burn-In test will expose the DUT (device under test) to harsh conditions: 150°C; relative humidity (RH): 85 rh; current rating: 1A continuous for 1000 hrs. In order to withstand conditions like that, C.C.P. modifies the plating material and core material. C.C.P. splits the socket into two parts: The standard part and the machining part. The standard part is manufactured by insert molding and holds the machining part which is customized according to the customers' IC design and made by CNC. The pins for the burn-in solution use a special material (WJ3) that shows an exceptional hardness and is able to withstand the demanding conditions posed by the Burn-In test.

Design Concept



Burn in Socket	Specification
IC Size	<15x15 mm²
Min. Pitch	0.3
Body Material	PES (Black)
Housing Material	Ultem2300
Operating Temperature	-55°C~180°C

Pogo Type Burn-in Socket

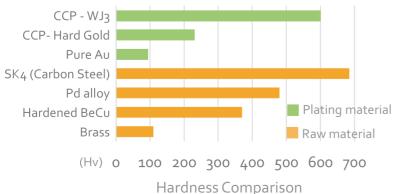
C.C.P. splits the socket into a standard part and a machining part. The standard part is processed by insert molding while the machining part is manufactured by CNC according to IC's size. This shortens the development time and reduces the mold tooling cost. C.C.P. can customize the sockets according to your needs.





Customized part Standard Part Manufactured according to IC size

Plating / Raw Material



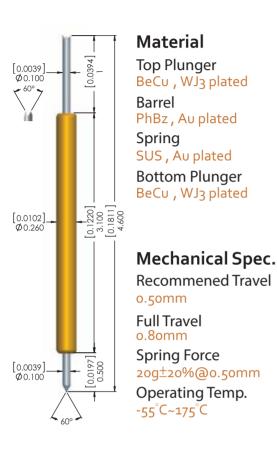
Commonly used in burn in test solution, WJ3 is a special plating material developed by C.C.P. and usually plated on the DUT side plunger. Besides high hardness, WJ3 is able to perform steadily in severe testing environments that reach 150°C for 1000 hours possibly even for 3000 hours.



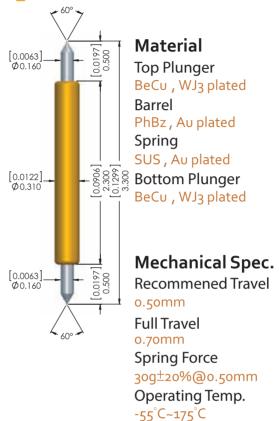
Unit:mm; []:in

C.C.P. Contact Probes Co., Ltd.

WE1-026EF31-01A0



WE1-031BB23-01A0



Electrical Spec.

Current Rating 1A continuous Contact Resistance $<175m\Omega(AVG)$ Characteristic Impedance 57Ω Insertion Loss -1dB>20GHz Return Loss -20dB@8.38GHz Time Delay 23.4 psec Loop Inductance 1.34 nH Capacitance 0.41pF

Electrical Spec.



Current Rating 1.5A continuous Contact Resistance <175m $\Omega(AVG)$ Characteristic Impedance 40.8 ∩ Insertion Loss -1dB>20 GHz Return Loss -20dB@ 5.3 GHz Time Delay 15.9 psec Loop Inductance 0.65 nH Capacitance 0.39 pF





Unit:mm; []:in

WE1-031BF23-01A0

[0.0063] Ø0.160 [0.0122] Ø0.310 [0.0063] Ø0.160

Material

Top Plunger BeCu, WJ3 plated Barrel PhBz, Au plated Spring SUS, Au plated **Bottom Plunger** BeCu, WJ₃ plated

Mechanical Spec. **Recommened Travel**

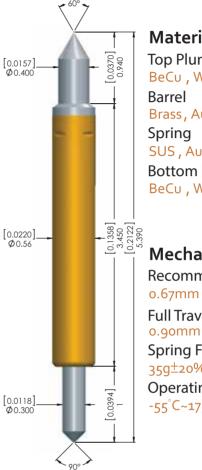
o.50mm **Full Travel** o.70mm Spring Force

30q±20%@0.50mm

Operating Temp.

-55°C~175°C

WE3-056BE34-02A0



Material

Top Plunger BeCu, WJ₃ plated Barrel Brass, Au plated Spring SUS, Au plated **Bottom Plunger** BeCu, WJ₃ plated

Mechanical Spec.

Recommened Travel 0.67mm **Full Travel**

Spring Force 35q±20%@0.67mm

Operating Temp. -55°C~175°C

Electrical Spec.



Current Rating 1.5A continuous Contact Resistance $<175m\Omega(AVG)$ Characteristic Impedance 33.72Ω Insertion Loss -1dB@12.51GHz Return Loss -2odB@2.49GHz Time Delay 17.2 psec Loop Inductance 0.58 nH Capacitance 0.51 pF

Electrical Spec.



Current Rating 5A continuous Contact Resistance <75m $\Omega(AVG)$ Characteristic Impedance 32.1Ω Insertion Loss -1dB@7GHz Return Loss -20dB@1.19 GHz Time Delay 29.5 psec Loop Inductance 0.95nH Capacitance 0.92 pF





Fin Pitch Conn. / FPC Test

A board to board connection requires fine-pitch pogo sockets to achieve the required accuracy. Pogo-Pin testing solutions have a significantly increased lifetime with more than 300,000 touchdowns. The excellent connectivity reduces the coplanarity error that occurs with traditional testing pins and results in improved efficiency of the testing procedures. C.C.P. has developed different kinds of testing pins that can be custo-mized according to the customer's needs.

Design Concept



Single-site pogo socket Pitch: 0.4mm



Fine Pitch Connector
Device under Test



Dual-site pogo socket with fine pitch connector (DUT)

Clip Pogo Socket

Clip pogo socket can hold the gold finger part on a PCB or an FPC. This solution is especially efficient and easy for PCB/FPC testing.

Specification
o.35mm
Acrylic/ Aluminum
Peek Ceramic
Aluminum
30,000





Gold FingerDevice under Test





DE1-030DF40-05A0

[0.0059] \$\phi_{0.150}\$ \$\phi_{0.150}\$ \$\phi_{0.0000}\$ \$\phi_{0.00000}\$ \$\phi_{0.0000}\$ \$\phi_{0.00000}\$ \$\phi_{0.0000}\$ \$\phi_{0.00000}\$ \$\phi_{0.0000}\$ \$\phi_{0.000

Material

Top Plunger SK4, Au plated Barrel PhBz, Au plated Spring SWP, Au plated Bottom Plunger BeCu, WJ3 plated

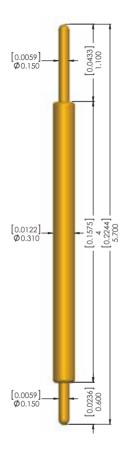
Mechanical Spec.

Recommened Travel 0.50mm Full Travel 1.00mm

Spring Force 25g±20%@0.50mm
Operating Temp.

-15°C~125°C

DE1-031DD40-01W1



Material

Top Plunger
SK4, Au plated
Barrel
PhBz, Au plated
Spring
SWP, Au plated
Bottom Plunger
SK4, Au plated

Mechanical Spec.

Recommened Travel

o.8omm

Full Travel

L.oomm

Spring Force 25q±20%@0.80mm

Operating Temp.

-15°C~125°C

Electrical Spec. Pitch: 0.4mm Socket Material: Peek 1000



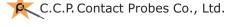
Current Rating 1A continuous Contact Resistance <175m Ω (AVG) Characteristic Impedance 44.8 Ω Insertion Loss -1dB>20GHz Return Loss -2odB@4.5GHz Time Delay 28.2 psec Loop Inductance 1.27nH Capacitance 0.63 pF

Electrical Spec.



Current Rating 1A continuous Contact Resistance <175m Ω (AVG) Characteristic Impedance 42.54 Ω Insertion Loss -1dB@18.82GHz Return Loss -2odB@3.41GHz Time Delay 26.8 psec Loop Inductance 1.14 nH Capacitance 0.63 pF





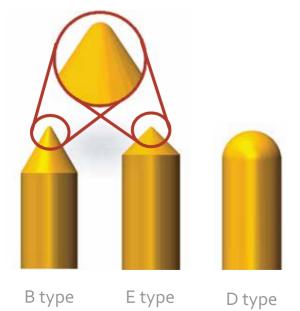
Panel Test

Most electronic devices use displays to interact with the user. Those displays are often fragile which requires appropriate testing solutions. Pogo pins are especially suitable for this type of application due to their customized tip, which protects the DUT from scratches.

Design Concept



Panel Pin Housing



Panel Test Housing

The housing is installed on a test head which contacts the panel directly. To protect the panel from damage, the head is rounded which prevents scratching of the panel surface.

Panel Pin Housing	Specification
Min. Pitch	o.45 mm
Panel Size	50"~85"
Housing Material	Peek
Life Time (Pin)	>200,000

Panel Pin Head Type

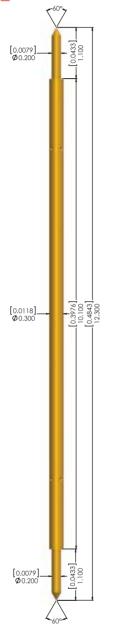
A conical tip is able to puncture oxide layers and has a low chance to leave scratches on the display. We usually recommend the D type for panel tests, to eliminate the chance of scratches.

B.C.E. s.r.l.



Unit:mm; []:in

DE1-030BB10-01A0



Material

Top Plunger Sk4, Au plated Barrel PhBz, Au plated Spring SWP, Au plated **Bottom Plunger** Sk4, Au plated

Mechanical Spec.

Recommened Travel

1.25mm

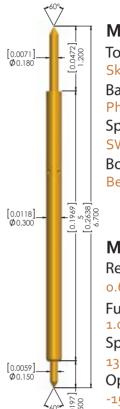
Full Travel 1.90mm Spring Force

20g±20%@1.25mm

Operating Temp.

-15°C~125°C

DE1-030BB50-01A0



Material

Top Plunger Sk4, Au plated Barrel PhBz, Au plated Spring SWP, Au plated **Bottom Plunger** BeCu, Au plated

Mechanical Spec.

Recommened Travel

0.65mm

Full Travel

1.00mm

Spring Force 13q±20%@0.65mm

Operating Temp.

-15°C~125°C

Electrical Spec. Pitch: 0.4mm Socket Material: Peek 1000



Current Rating 1A continuous Contact Resistance $<175m\Omega(AVG)$ Characteristic Impedance 67Ω Insertion Loss -1dB@3.34GHz Return Loss -2odB@o.87GHz Time Delay 67.01 psec Loop Inductance 4.49 nH

Capacitance 1 pF

Electrical Spec. Pitch: 0.4mm Socket Material: Peek 1000





Current Rating 1A continuous Contact Resistance $<175m\Omega(AVG)$ Characteristic Impedance 45Ω Insertion Loss -1dB >20GHz Return Loss -2odB@3.35GHz Time Delay 32.8 psec Loop Inductance 1.48 nH Capacitance 0.73 pF

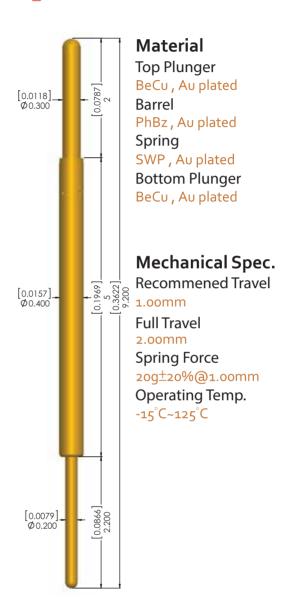


Unit:mm; []:in

DE3-031DD50-01A0

Material Top Plunger BeCu, Au plated PhBz, Au plated Spring SWP, Au plated **Bottom Plunger** BeCu, Au plated Mechanical Spec. 0.2000] 5.080 0.3575] 9.080 [0.0122] Ø0.310 **Recommened Travel** 1.00mm **Full Travel** 2.00mm **Spring Force** 20q±20%@1.00mm Operating Temp. -15°C~125°C

DE3-040DD50-01A0



Electrical Spec. Pitch: 0.4mm Socket Material: Peek 1000

[0.0071] Ø0.180



Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 41.54Ω Insertion Loss -1dB@14.66GHz Return Loss -2odB@2.o3GHz Time Delay 42.37 psec Loop Inductance 1.76 nH Capacitance 1.02 pF

Time Delay 46.76 psec Loop Inductance 1.97 nH

Capacitance 1.11 pF

Electrical Spec.

Pitch: 0.5mm Socket Material: Peek 1000

Current Rating 1A continuous

Insertion Loss -1dB@10.93GHz Return Loss -2odB@2.05GHz

Contact Resistance $<75m\Omega(AVG)$

Characteristic Impedance 42.13Ω



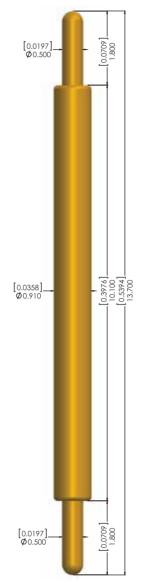


Unit:mm; []:in

DE3-040DD85-01A0

Material Top Plunger [0.1378] [0.0118] BeCu, Au plated PhBz, Au plated Spring SUS, Au plated **Bottom Plunger** BeCu, Au plated Mechanical Spec. [0.3366]-8.550 -[0.612]. 15.550 **Recommened Travel** [0.0157] 2.50mm Ø 0 400 **Full Travel** 3.00mm **Spring Force** 20g±20%@2.50mm Operating Temp. -55°C~150°C [0.1378] 3.500 [0.0079] Ø0.200

DE1-091DD10-01A0



Material Top Plunger

BeCu, Au plated Barrel PhBz, Au plated Spring SWP, Au plated **Bottom Plunger** BeCu, Au plated

Mechanical Spec.

Recommened Travel

2.00mm **Full Travel** 3.00mm Spring Force 20g±20%@2.00mm Operating Temp. -15°C~125°C

Electrical Spec.



Current Rating 1A continuous Contact Resistance $<75m\Omega(AVG)$ Characteristic Impedance 40Ω Insertion Loss -1dB@6.08GHz Return Loss -2odB@1.06GHz Time Delay 74.8 psec Loop Inductance 3 nH Capacitance 1.87 pF

Electrical Spec.



Current Rating ^{2A} continuous Contact Resistance <175m $\Omega(AVG)$ Characteristic Impedance $^{24.2}\Omega$ Insertion Loss -1dB@1.52GHz Return Loss -20dB@0.28GHz Time Delay 72.6 psec Loop Inductance 1.76 nH Capacitance 3 pF

ATE Connection Solutions



ATE Connection

Pogo towers and adapters are usually used to connect a motherboard and a daughterboard in automatic testing equipment. C.C.P. has developed ATE connecting solutions for several years. Testing equipment such as J750 and V93000 are well-established solutions.

Design Concept

A pogo tower can be customized according to you requirements such as frequency or pitch.



Pogo tower (line)



Pogo tower (ring)



B.C.E. s.r.l.

Pogo tower (line)	Specification
Housing Material	FR4
Pitch	2.54
Insertion Loss	-3dB@2.4GHz
Pogo tower (ring)	Specification
Housing Material	FR4
Pitch	2.54
Insertion Loss	-3dB@2.4GHz
Pogo cable	Specification
Housing Material	FR ₄
Pitch	2.54
Insertion Loss	-3dB@2.4GHz
Impedance	





Cleaning Tools



Nylon Brush SSP-SSN-906500

Wire Diameter: Φ0.1mm

Size: 2.1 mm*4.0 mm*L145 mm



Steel Brush SSP-SSS-SST6SS

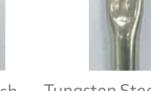
Wire Diameter: Φ0.1mm

Size: 3.5mm*6.5 mm*L130 mm



Steel Brush SSP-SSS-SST2SS

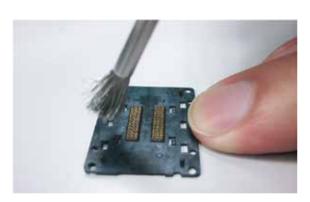
Wire Diameter: Φ0.1mm Size: 2.0 mm*4.5mm*L93 mm



Tungsten Steel Brush SSP-BR-TS002-094

Wire Diameter: Φ0.0 mm Size: 1.7 mm*4.2 mm*L94 mm

Probe Cleaning



Particles can interfere with the test result and decrease the yield rate. Probe cleaning can avoid this situation from happening. We can provide various cleaning tooling for persistent solder splashes or particles on the probe tip.

Slightly brush the probe tip to remove particle or tin on it.



Probe damage level:

Nylon brush

- < Nano Tungsten steel brush
- < Steel Brush (smaller brush size)
- < Steel Brush (bigger brush size)



No Damage

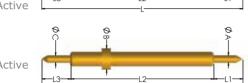




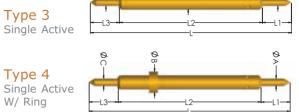




Type 1
Double Active



Type 3
Single Active



Type 2 Double Active W/ Ring

										Un	it: mm
Pitch	P/N	Туре	Total Length (L)	Barrel /Ring OD (φB)	Plunger A Type/ Length (L1)	Plunger A OD (\$A)	Plunger C Type/ Length (L ₃)	Plunger C OD (φC)	Working Stroke	Spring Force ±20% @Working Stroke	Detail Spec (page)
	PE1-010EE20-01A0	1	3.00	0.10	Conical/ 0.40	0.045	Conical/ o.4o	0.045	0.35	79	6
0.2	PE3-010DS53-02A0		7.00	0.175	Serrated/ 0.70	0.13	Round/ 0.90	0.08	0.55	6g	28
0.2	PE3-013DS53-01F0	3	7.00	0.175	Serrated/ 0.70	0.13	Round/ 0.90	0.09	0.55	6g	28
	PE3-015DL38-01A0	3	5.50	0.15	Blade/ o.8o	0.14	Round/ o.8o	0.11	0.40	20g	39
	PE3-020EL31-01A0		4.75	0.20	Blade/ 0.95	0.19	Conical/ o.6o	0.10	0.30	10g	39
0.3	DE1-020BE40-01A0	3	5.70	0.20	Conical/ 1.10	0.10	Conical/ 0.60	0.10	0.60	12g	6
0.5	PE3-020DS53-01A0	3	7.00	0.23	Serrated/ 0.70	0.19	Round/ 0.90	0.10	0.55	259	29
	DE1-020BE74-010	1	9.70	0.20	Conical/ 1.50	0.19	Conical/ o.8o	0.10	0.80	6g	
	DE1-025BB10-02A0		12.20	0.25	Conical/ 1.10	0.13	Conical/ 1.10	0.12			7
	PE4-025EF24-01A0	1	3.30	0.32	Crown/ 0.25	-	Conical/ 1.10	0.13	1.45	30g	7
		4		0.32	Crown/ 0.25	0.24	Conical/ 0.50		0.40	239	8
	PE3-026DF17-01F0 PE3-026BD18-01A0	3	3.00 2.87	0.18	Conical/ 0.52	0.15	Round/ 0.50	0.12	0.35	20g	
		3	,	0.16	Crown/ o.60		Round/ 0.85	0.13	0.30	249	9
	PE3-026DF27-01F0	3	4.25 4.60	0.26	Crown/ 1.00	0.15	Conical/ 0.50	0.13	0.40	22g	9
	WE1-026EF31-01A0	1		0.26	Conical/ 1.10	0.10	Conical/ 0.50	0.10	0.50	20g	45
	DE1-026BE40-01A0	1	5.70		Crown/ 1.10	0.10	Round/ o.6o	0.10	0.65	149	10
	DE1-026DF40-02A0	1	5.70	0.26		0.11		0.11	0.65	18g	10
	DE3-026EF49-01A0	3	7.20	0.26	Crown/ 1.30	0.17	Conical/ 0.90	0.12	0.70	20g	11
	PE4-028DE09-01A0	4	1.23	0.33	- Corretadio (F	-	Round/ 0.26	0.13	0.18	159	36
	DE4-029DW25-01A0		3.70	0.33	Serrated/ 0.45 Crown/ 0.75	0.27	Round/ 0.70	0.12	0.40	259	31
	DE4-029FF45-01A0	4	6.50	0.34		0.22	Crown/ 1.10	0.15	0.70	3og	11
	DE1-030BB10-01A0	1	12.30	0.30	Conical/ 1.10	0.20	Conical/ 1.10	0.20	1.25	20g	50
	DE1-030BB50-01A0	1	6.7	0.30	Conical/ 1.20	0.18	Conical/ 0.50	0.15	0.65	139	50
	PE3-030DF17-03A0	3	3.25	0.30	Crown/ o.95	0.18	Round/ 0.50	0.16	0.35	279	12
0.4	PE3-030DF18-01A0	3	2.90	0.30	Crown/ o.6o	0.20	Round/ 0.50	0.15	0.40	359	12
	DE3-030BF21-03F0	3	3.30	0.30	Crown/ o.6o	0.22	Conical/ 0.60	0.15	0.40	3og	13
	PE3-030EL25-01A0	3	3.89	0.30	Blade/ o.68	0.20	Conical/ 0.65	0.15	0.45	259	40
	DE1-030DF40-05A0	3	5.70	0.30	Crown/ 1.10	0.15	Round/ o.6o	0.15	0.50	25g	48
	PE3-030EF53-01A0	3	7.00	0.30	Crown/ 0.70	0.20	Conical/ 0.90	0.15	0.55	25g	29
	PE3-031DF17-03F0	3	2.85	0.31	Crown/ 0.55	0.20	Round/ 0.50	0.16	0.35	359	13
	PE3-031DF21-03F0	3	3.30	0.31	Crown/ 0.50	0.20	Round/ o.6o	0.16	0.40	359	14
	WE1-031BB23-01A0	1	3.30	0.31	Conical/ 0.50	0.16	Conical/ 0.50	0.16	0.50	25g	45
	WE1-031BF23-01A0	1	3.30	0.31	Crown/ 0.50	0.16	Conical/ 0.50	0.16	0.50	3og	46
	PE1-031EF23-02F0	1	3.30	0.31	Crown/ o.6o	0.16	Conical/ 0.40	0.16	0.40	3og	14
	PE1-031EF30-02F0	1	4.00	0.31	Crown/ o.6o	0.16	Conical/ 0.40	0.16	0.60	31g	15
	PE1-031DF30-01F0	1	4.00	0.31	Crown/ o.6o	0.16	Round/ 0.40	0.16	0.60	31g	15
	DE1-031BF32-02A0	1	4.75	0.31	Conical/ 1.10	0.16	Crown/ 0.45	0.16	0.60	25g	16
	PE3-031EL38-01A0	3	5.44	0.31	Blade/ 0.77	0.30	Conical/ 0.87	0.15	0.60	359	40
	DE1-031DD40-01W1	3	5.70	0.31	Round/ 1.10	0.15	Round/ o.6o	0.15	0.80	25g	48
	DE3-031DD50-01A0	3	9.08	0.31	Round/ 2.00	0.23	Round/ 2.00	0.18	1.00	20g	51
	PE4-032DF24-03F0	4	3.30	0.39	Crown/ o.30	0.31	Round/ o.6o	0.15	0.40	3og	16

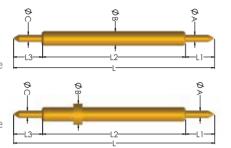
Except the specifications in the table, we provide customization according to your specifications.





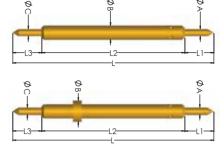
Type 1
Double Active

Type 2
Double Active
W/ Ring



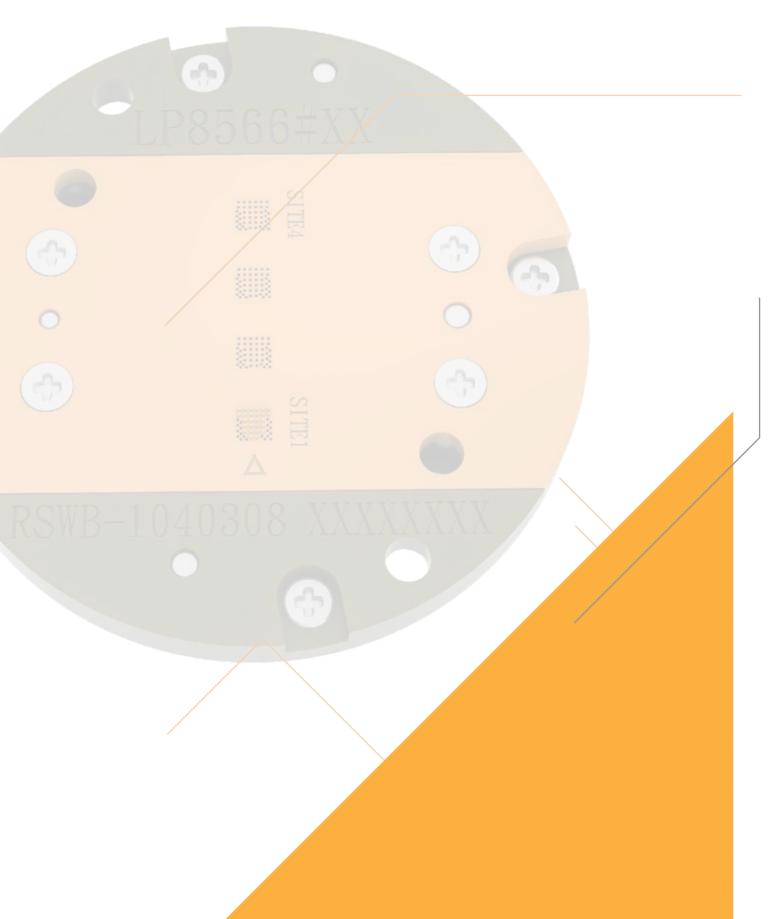
Type 3
Single Active

Type 4
Single Active
W/ Ring



Unit: mm

										UII	it: mm
Pitch	P/N	Type	Total Length	Barrel /Ring OD	Plunger A Type/ Length	Plunger A OD	Plunger C Type/ Length	Plunger C OD	Working Stroke	Spring Force ±20% @Working	Detail Spec (page)
PILCII	F/IN	Type	(L)	(φB)	(L1)	(фА)	(L ₃)	(фС)		Stroke	(page)
	PE4-035DE09-01H0	4	1.23	0.43	-	-	Round/ 0.26	0.17	0.18	159	36
	DE1-035BE12-01A0	1	2.00	0.35	Conical/ 0.50	0.20	Conical/ 0.30	0.20	0.30	18g	17
	DE4-035DH24-01A0	4	3.35	0.42	Serrated/ 0.25	0.33	Round/ 0.70	0.18	0.50	279	43
	PE4-035DF24-01F0	4	3.35	0.40	Crown/ 0.25	0.34	Round/ 0.70	0.20	0.45	32g	17
	PE1-035EF25-01F0	1	3.50	0.35	Crown/ o.6o	0.20	Conical/ 0.40	0.20	0.60	32g	18
	PE3-038DF17-03F0	3	3.15	0.38	Crown/ 0.75	0.23	Round/ 0.55	0.20	0.38	38g	18
0.5	PE3-038EF17-04A0	3	2.85	0.38	Crown/ o.50	0.22	Conical/ 0.50	0.22	0.35	3og	19
	PE1-038DF32-02F0	1	4.80	0.38	Crown/ 1.10	0.21	Round/ 0.55	0.20	0.65	379	19
	PE1-038EP40-01A0	1	5.70	0.38	Crown/ 1.10	0.22	Conical/ o.6o	0.22	0.65	40g	20
	PE3-040BF34-01A0	3	5.70	0.40	Crown/ 1.13	0.32	Conical/ 1.07	0.22	0.70	3og	20
	DE1-040BF39-030	1	5.20	0.40	Crown/ o.65	0.23	Conical/ o.65	0.20	0.65	259	21
	DE3-040DD50-01A0	3	9.20	0.40	Round/ 2.00	0.30	Round/ 2.20	0.20	1.00	20g	51
	DE3-040DD85-01A0	3	15.55	0.40	Round/ 3.50	0.30	Round/ 3.50	0.20	2.50	22g	52
	PE4-045EF09-01A0	4	1.50	0.54	-	-	Conical/ 0.55	0.28	0.40	30g	37
	DE4-048EF17-01F0	4	2.65	0.55	Crown/ 0.20	0.47	Conical/ 0.75	0.25	0.50	27.5g	21
	DE2-050EF25-120	2	3.40	0.65	Crown/ o.50	0.30	Conical/ 0.35	0.30	0.40	359	42
0.6	PE2-050EF25-01F0	2	3.35	0.66	Crown/ o.50	0.30	Conical/ 0.30	0.30	0.45	359	22
	PE4-052DF17-01F0	4	2.57	0.62	Crown/ o.3o	0.51	Round/ 0.57	0.25	0.40	3og	22
	PE4-052DF28-01F0	4	4.20	0.60	Crown/ o.40	0.51	Round/ 1.00	0.25	0.60	4og	23
	DE4-052EF23-02F0	4	3.35	0.61	Crown/ o.3o	0.50	Conical/ 0.75	0.30	0.45	359	24
	DE4-056EF09-03F0	4	1.50	0.65	-	-	Conical/ 0.55	0.38	0.40	31g	42
	PE4-056EF09-01H0	4	1.50	0.65	-	-	Conical/ 0.55	0.38	0.40	31g	37
	PE4-056DF20-02F0	4	3.05	0.65	Crown/ o.3o	0.54	Round/ 0.70	0.30	0.50	359	24
0.7	DE3-056BE34-01A0	3	5.39	0.56	Conical/ 0.94	0.40	Conical/ 1.00	0.30	0.67	359	31
	WE3-056BE34-02A0	4	5.39	0.56	Conical/ 0.94	0.40	Conical/ 1.00	0.30	0.67	359	46
	PE1-058EE40-01A0	1	5.75	0.58	Conical/ 1.10	0.30	Conical/ o.65	0.30	0.80	28g	43
	PE4-065EW15-01A0	4	2.5	0.65	Serrated/ o.6o	0.53	Conical/ 0.70	0.42	0.50	32g	24
o.8	PE4-068EP35-01F0	4	4.45	0.80	Crown/ o.40	0.67	Conical/ o.9o	0.35	0.65	4og	25
	DE1-072EE50-01A0	1	7.20	0.72	Conical/ 1.70	0.40	Conical/ 0.50	0.40	1.20	20g	25
0.9	DE1-080BF40-010	1	5.80	0.80	Crown/ 1.15	0.50	Conical/ o.65	0.50	0.70	3og	26
	DE4-090EF25-02F0	4	3.20	1.00	Crown/ o.40	0.90	Conical/ 0.70	0.63	0.50	30g	26
1.0	DE1-091DD10-01A0	1	13.70	0.91	Round/ 1.80	0.50	Round/ 1.80	0.50	2.00	50g	52







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